Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/853,661	TANAKA, MASAHIRO	
Examiner	Art Unit	
José R. Díaz	2815	

	SEARCHED					
Class	Subclass	Date	Examiner			
257	262,342, 655	5/16/2005	JRD			
		- · ·				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	<u> </u>				

(INCLUDING SEARCH	ISTRATEGY)
	DATE	EXMR
Text Search East: IGBT and anode	5/16/2005	JRD
, ,		
•	·	